

## **REPLACEMENT OF THE ABSTRACT OF THE DISCLOSURE:**

*Please replace the Abstract and replace it with the following:*

The present invention provides Provided are a device, method and storage medium, ~~stored with software programs, which, when a memory LSI defect analysis apparatus is used as a monitoring device to estimate reductions in yield, can shorten the time needed for full manual interpretation of the obtained results, by~~ interprets interpreting the analyzed results obtained, and calculates calculating the period of distribution patterns and the mix rate of regular patterned defects. ~~First in defect number calculation process 71, the~~ The total defect number of bits is found,; ~~and in factor selection process 61, the factor  $f_i$  is then selected. Next, in regular patterned decision process 62, the~~ The value of expected value function,  $T(f)$ , for the selected  $f$  is found, and it is decided whether or not it includes regularly patterned defects; and if it is decided that regularly patterned defects are included (~~process 63~~), then ~~in regular patterned defect mix rate function calculation process 73,~~ regular pattern defect mix rate function  $MR(f)$  is calculated from number of bits  $n$ , factor  $f$ , and the value of estimated value function  $T(f)$ . If it is decided that it does not contain regularly patterned defects (~~process 65~~), ~~in regular patterned defect mix rate function calculation process 66,~~ the regular patterned defect mix rate function  $MR(f)$  is assumed to be zero; and finally, ~~in  $MR(f)$  calculation completion confirmation process 67,~~ it is confirmed whether or not  $MR(f)$  has been found for every  $f$ ; and if there are factors for which  $MR(f)$  has not been found, then it returns to process 61.